Issue Classification

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Examiner

Bétit, Jacob F

Applicant(s)/Patent Under Reexamination

CHANG ET AL.

Art Unit

2164

ORIGINAL						INTERNATIONAL CLASSIFICATION										
CLASS SL				SUBCLASS	CLAIMED					NON-CLAIMED					AIMED	
707 3					G	0	6	F	7 / 00 (20	06.0)						
CROSS REFERENCE(S)			S)		G	0	6	F	17 / 30 (2006.0	1.01)						
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Bésit, Jacob F 45 avr 07 (Assistant Examiner) (Date)			1	CHARLES RONES SUPERVISORY PATENT EXAMINER							Total Claims Allowed:					
					1-7-08						O.G. Print Claim(s)				O.G. Print Figure	
(Legal Instruments (Date) Examiner)			(Primary	(Primary Examiner) (Date)				Date)	1 9							